

(54) Title of the invention : AN APPARATUS FOR ANALYZING QUALITY OF SEED

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(57) Abstract :

An apparatus for analyzing quality of seed sample is disclosed. According to an embodiment the apparatus for analyzing quality of seed sample can include a hopper configured to receive seed sample, a source configured to direct one or more incident radiations towards the received seed sample and a set of sensors configured to detect the one or more incident radiations after the one or more incident radiations has interacted with the seed sample. An analyzer is configured to determine one or more parameters associated with quality of the seed sample based on the one or more detected radiations. The apparatus is portable.

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